SEP 2 2 2003 B

CEDE 2111 PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Abayomi I. Owei, et al. Serial No. 10/619,198 Filed July 14, 2003 For ADHESION PROMOTION IN PRINTED CIRCUIT BOARDS

September 22, 2003

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INFORMATION DISCLOSURE STATEMENT

In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit copies of the references listed on the attached PTO/SB/08A for consideration by the Patent and Trademark Office in the above-entitled application and to be made of record therein.

Respectfully submitted,

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PIF/leb

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PTO/SB/08A	Complete if Known			
INFORMATION DISCLOSURE	Application Number	10/619,198		
STATEMENT BY APPLICANT	Filing Date	07-14-2003		
(use as many sheets as necessary)	Confirmation Number			
(use as many sheets as necessary)	First Named Inventor	Owei et al.		
SEP 1 2 2003 11	Group Art Unit			
	Examiner Name			
Sheet TRADE Of 3	Attorney Docket No.	CEDE 2111		

		U	.S. PATENT	DOCUMENTS		
		U.S. Patent Doc	ument		Date of Publication of Cited Document MM-DD-YYYY	
	Cite No.1	Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document		
	1	2002/0038790		Kurii et al.	04-04-2002	
	2	4,051,057		Ericson et al.	09-27-1977	
	3	5,106,454		Allardyce et al.	04-21-1992	
	4	5,261,154		Ferrier et al.	11-16-1993	
	5	5,289,630		Ferrier et al.	03-01-1994	
	6	5,435,860		Maki et al.	07-25-1995	
	7	5,439,783		Akiyama et al.	08-08-1995	
	8	5,468,515		Ferrier et al.	11-21-1995	
	9	5,476,947		Maki et al.	12-19-1995	
	10	5,496,590		Maki et al.	03-05-1996	
	11	5,518,760		Ferrier et al.	05-21-1996	
	12	5,532,094		Arimura et al.	07-02-1996	
	13	5,536,386		Ferrier et al.	07-16-1996	
	14	5,632,927		Ferrier et al.	05-27-1997	
	15	5,700,389		Nakagawa	12-23-1997	
	16	5,733,599		Ferrier et al.	03-31-1998	
Examiner Signature				Date Considered		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

^{&#}x27;Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached or place an "A" here if English language abstract is attached.

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					Examiner Name			
Sheet	2	of	3		Atto	rney Docket No.		CEDE 2111
<u> </u>	17	5,759,378			F	errier et al.		06-02-1998
	18	5,800,859				Price et al.		09-01-1998
	19	5,807,493				/laki et al.		09-15-1998
	20	5,869,130			F	errier		02-09-1999
	21	5,885,476			Hong et al.		03-23-1999	
	22	5,935,640 5,965,036			F	errier et al.		08-10-1999
	23				Maki et al.		10-12-1999	
	24	6,020,029			Ferrier et al.		02-01-2000	
	25	6,036,758			F	airweather		03-14-2000
	26	6,054,061			Bayes et al. McGrath et al.		04-25-2000	
	27	6,074,803						06-13-2000
	28	6,146,701			F	errier		11-14-2000
	29	6,162,503			F	errier		12-19-2000
	30	6,261,466			E	Bayes et al.		07-17-2001
	31	6,284,309			E	Bishop et al.		09-04-2001
	32	6,294,220			^	McGrath et al.		09-25-2001
	33	6,383,272			F	errier		05-07-2002
	34	6,419,784			F	errier		07-16-2002
	35	6,475,316			_ P	Kirk et al.		11-05-2002
	36	6,506,314			Whitney, Jr. et al.		01-14-2003	
	37	6,544,436				Morikawa et al.		04-08-2003
Examiner Signature						Date Considered		

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PTO/SB/08A				Complete if Known						
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						Group Art Unit				
Sheet 3 of 3			Examiner Name							
Sheet	BADEMAS	<u>, </u>	of	3		Attorney Docket No.			CEDE 2111	
								<u></u>		
	38	6,562,149				Grieser et al.			05-13-2003	
				FOREIG	SN PA	TE	ENT DOCUMENTS			
	Foreign Patent Document				ent					
Examiner Initials*	Cite No.1	Office	Number ⁴	ı	Kind Code ² (if known)		Name of Patentee or Applicant Cited Document		Date of Publication of Cited Document MM-DD-YYYY	76
		OTH	IER AR	T - NON	PATE	EN'	T LITERATURE DOCUM	MEN	TS	
Examiner Initials* Cite No.1 Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.								T _€		

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Declaration of Abayomi I. Owei and David Ormerod

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